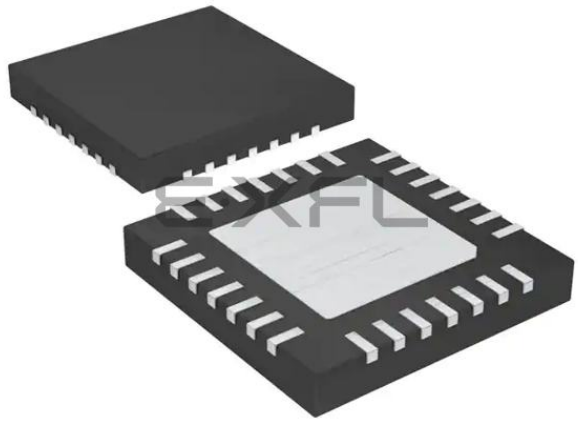
Silicon Labs - EFM8BB22F16G-C-QFN28R Datasheet



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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	50MHz
Connectivity	I²C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	22
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 20x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	28-WFQFN Exposed Pad
Supplier Device Package	28-QFN (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8bb22f16g-c-qfn28r

1. Feature List

The EFM8BB2 highlighted features are listed below.

- Core:
  - Pipelined CIP-51 Core
  - Fully compatible with standard 8051 instruction set
  - 70% of instructions execute in 1-2 clock cycles
  - 50 MHz maximum operating frequency
- Memory:
  - Up to 16 KB flash memory, in-system re-programmable from firmware, including 1 KB of 64-byte sectors and 15 KB of 512-byte sectors.
  - Up to 2304 bytes RAM (including 256 bytes standard 8051 RAM and 2048 bytes on-chip XRAM)
- Power:
  - 5 V-input LDO regulator
  - Internal LDO regulator for CPU core voltage
  - Power-on reset circuit and brownout detectors
- I/O: Up to 22 total multifunction I/O pins:
  - All pins 5 V tolerant under bias
  - Flexible peripheral crossbar for peripheral routing
  - 5 mA source, 12.5 mA sink allows direct drive of LEDs
- Clock Sources:
  - Internal 49 MHz oscillator with accuracy of ±1.5%
  - Internal 24.5 MHz oscillator with ±2% accuracy
  - Internal 80 kHz low-frequency oscillator
  - External CMOS clock option
- Timers/Counters and PWM:
  - 3-channel Programmable Counter Array (PCA) supporting PWM, capture/compare, and frequency output modes
  - 5 x 16-bit general-purpose timers
  - Independent watchdog timer, clocked from the low frequency oscillator
- Communications and Digital Peripherals:
  - 2 x UART, up to 3 Mbaud
  - SPI™ Master / Slave, up to 12 Mbps
  - SMBus™/I2C™ Master / Slave, up to 400 kbps
  - I^2C High-Speed Slave, up to 3.4 Mbps
  - 16-bit CRC unit, supporting automatic CRC of flash at 256-byte boundaries
- Analog:
  - 12-Bit Analog-to-Digital Converter (ADC)
  - 2 x Low-current analog comparators with adjustable reference
- On-Chip, Non-Intrusive Debugging
  - Full memory and register inspection
  - Four hardware breakpoints, single-stepping
- Pre-loaded UART bootloader
- Temperature range -40 to 85 ºC or -40 to 125 ºC
  - Automotive grade available (requires PPAP)
- Single power supply of 2.2 to 3.6 V or 3.0 to 5.25 V
- QFN28, QSOP24, and QFN20 packages

With on-chip power-on reset, voltage supply monitor, watchdog timer, and clock oscillator, the EFM8BB2 devices are truly standalone system-on-a-chip solutions. The flash memory is reprogrammable in-circuit, providing nonvolatile data storage and allowing field upgrades of the firmware. The on-chip debugging interface (C2) allows non-intrusive (uses no on-chip resources), full speed, in-circuit debugging using the production MCU installed in the final application. This debug logic supports inspection and modification of memory and registers, setting breakpoints, single stepping, and run and halt commands. All analog and digital peripherals are fully functional while debugging. Each device is specified for 2.2 to 3.6 V operation (or up to 5.25 V with the 5 V regulator option) and is available in 28-pin QFN, 20-pin QFN, or 24-pin QSOP packages. All package options are lead-free and RoHS compliant.

2. Ordering Information

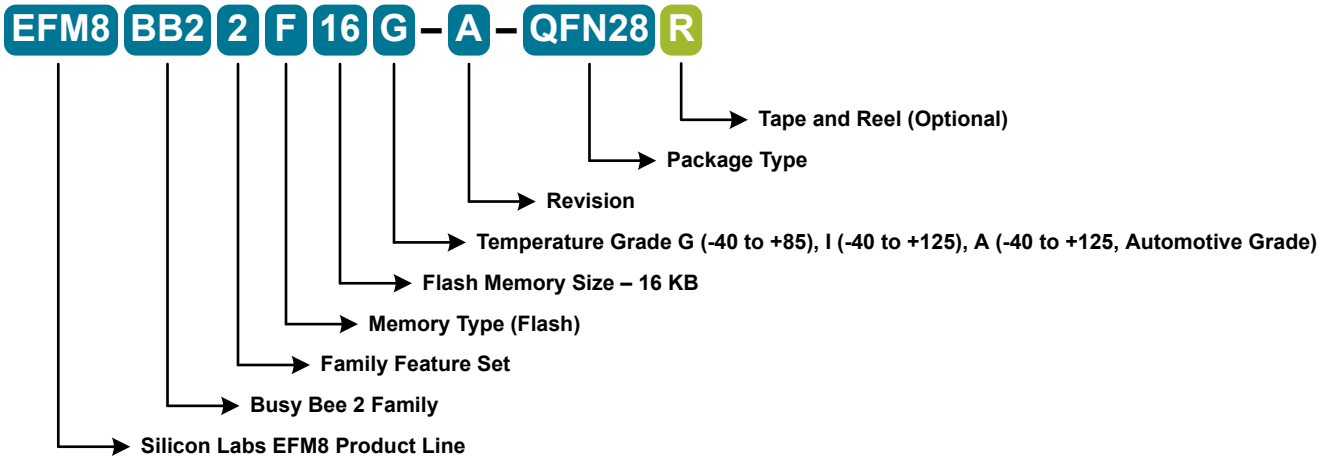

Figure 2.1. EFM8BB2 Part Numbering

All EFM8B2 family members have the following features:

- CIP-51 Core running up to 50 MHz
- Three Internal Oscillators (49 MHz, 24.5 MHz and 80 kHz)
- SMBus
- I2C Slave
- SPI
- 2 UARTs
- 3-Channel Programmable Counter Array (PWM, Clock Generation, Capture/Compare)
- 5 16-bit Timers
- 2 Analog Comparators
- 12-bit Analog-to-Digital Converter with integrated multiplexer, voltage reference, and temperature sensor
- 16-bit CRC Unit
- AEC-Q100 qualified
- Pre-loaded UART bootloader

In addition to these features, each part number in the EFM8BB2 family has a set of features that vary across the product line. The product selection guide shows the features available on each family member.

Table 2.1. Product Selection Guide

Ordering Part Number	Flash Memory (KB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Comparator 0 Inputs	Comparator 1 Inputs	Pb-free (RoHS Compliant)	5-to-3.3 V Regulator	Temperature Range	Package
EFM8BB22F16G-C-QFN28	16	2304	22	20	10	12	Yes	Yes	-40 to +85 ºC	QFN28
EFM8BB21F16G-C-QSOP24	16	2304	21	20	10	12	Yes	—	-40 to +85 ºC	QSOP24
EFM8BB21F16G-C-QFN20	16	2304	16	15	10	7	Yes	—	-40 to +85 ºC	QFN20
EFM8BB22F16I-C-QFN28	16	2304	22	20	10	12	Yes	Yes	-40 to +125 ºC	QFN28
EFM8BB21F16I-C-QSOP24	16	2304	21	20	10	12	Yes	—	-40 to +125 ºC	QSOP24

Ordering Part Number	Flash Memory (KB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Comparator 0 Inputs	Comparator 1 Inputs	Pb-free (RoHS Compliant)	5-to-3.3 V Regulator	Temperature Range	Package
EFM8BB21F16I-C-QFN20	16	2304	16	15	10	7	Yes	—	-40 to +125 ºC	QFN20
EFM8BB22F16A-C-QFN28	16	2304	22	20	10	12	Yes	Yes	-40 to +125 ºC	QFN28
EFM8BB21F16A-C-QFN20	16	2304	16	15	10	7	Yes	—	-40 to +125 ºC	QFN20

The A-grade (i.e. EFM8BB21F16A-C-QFN20) devices receive full automotive quality production status, including AEC-Q100 qualification, registration with International Material Data System (IMDS), and Part Production Approval Process (PPAP) documentation. PPAP documentation is available at www.silabs.com with a registered and NDA approved user account.

Low Current Comparators (CMP0, CMP1)

Analog comparators are used to compare the voltage of two analog inputs, with a digital output indicating which input voltage is higher. External input connections to device I/O pins and internal connections are available through separate multiplexers on the positive and negative inputs. Hysteresis, response time, and current consumption may be programmed to suit the specific needs of the application.

The comparator includes the following features:

- Up to 10 (CMP0) or 12 (CMP1) external positive inputs
- Up to 10 (CMP0) or 12 (CMP1) external negative inputs
- Additional input options:
  - Internal connection to LDO output
  - Direct connection to GND
  - Direct connection to VDD
  - Dedicated 6-bit reference DAC
- Synchronous and asynchronous outputs can be routed to pins via crossbar
- Programmable hysteresis between 0 and ±20 mV
- Programmable response time
- Interrupts generated on rising, falling, or both edges
- PWM output kill feature

3.8 Reset Sources

Reset circuitry allows the controller to be easily placed in a predefined default condition. On entry to this reset state, the following occur:

- The core halts program execution.
- Module registers are initialized to their defined reset values unless the bits reset only with a power-on reset.
- External port pins are forced to a known state.
- Interrupts and timers are disabled.

All registers are reset to the predefined values noted in the register descriptions unless the bits only reset with a power-on reset. The contents of RAM are unaffected during a reset; any previously stored data is preserved as long as power is not lost. The Port I/O latches are reset to 1 in open-drain mode. Weak pullups are enabled during and after the reset. For Supply Monitor and power-on resets, the RSTb pin is driven low until the device exits the reset state. On exit from the reset state, the program counter (PC) is reset, and the system clock defaults to an internal oscillator. The Watchdog Timer is enabled, and program execution begins at location 0x0000.

Reset sources on the device include the following:

- Power-on reset
- External reset pin
- Comparator reset
- Software-triggered reset
- Supply monitor reset (monitors VDD supply)
- Watchdog timer reset
- Missing clock detector reset
- Flash error reset

3.9 Debugging

The EFM8BB2 devices include an on-chip Silicon Labs 2-Wire (C2) debug interface to allow flash programming and in-system debugging with the production part installed in the end application. The C2 interface uses a clock signal (C2CK) and a bi-directional C2 data signal (C2D) to transfer information between the device and a host system. See the C2 Interface Specification for details on the C2 protocol.

4. Electrical Characteristics

4.1 Electrical Characteristics

All electrical parameters in all tables are specified under the conditions listed in Table 4.1 Recommended Operating Conditions on page 12, unless stated otherwise.

4.1.1 Recommended Operating Conditions

Table 4.1. Recommended Operating Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Operating Supply Voltage on VDD	V_{DD}		2.2	—	3.6	V
Operating Supply Voltage on VREGIN	V_{REGIN}		3.0	—	5.25	V
System Clock Frequency	f_{SYSCLK}		0	—	50	MHz
Operating Ambient Temperature	T_A	G-grade devices	-40	—	85	°C
		I-grade or A-grade devices	-40	—	125	°C

Note:

1. All voltages with respect to GND.
2. GPIO levels are undefined whenever VDD is less than 1 V.

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Stop Mode—Core halted and all clocks stopped,Internal LDO On, Supply monitor off.	I_{DD}		—	120	1045	µA
Shutdown Mode—Core halted and all clocks stopped,Internal LDO Off, Supply monitor off.	I_{DD}		—	0.2	15	µA
Analog Peripheral Supply Currents (-40 °C to +125 °C)						
High-Frequency Oscillator 0	I_{HFOSC0}	Operating at 24.5 MHz, T_A = 25 °C	—	105	—	µA
High-Frequency Oscillator 1	I_{HFOSC1}	Operating at 49 MHz, T_A = 25 °C	—	865	940	µA
Low-Frequency Oscillator	I_{LFOSC}	Operating at 80 kHz, T_A = 25 °C	—	4	—	µA
ADC0 Always-on[4]	I_{ADC}	800 ksps, 10-bit conversions or 200 ksps, 12-bit conversions Normal bias settings V_{DD} = 3.0 V	—	820	1200	µA
		250 ksps, 10-bit conversions or 62.5 ksps 12-bit conversions Low power bias settings V_{DD} = 3.0 V	—	405	580	µA
ADC0 Burst Mode, 10-bit single conversions, external reference	I_{ADC}	200 ksps, V_{DD} = 3.0 V	—	370	—	µA
		100 ksps, V_{DD} = 3.0 V	—	185	—	µA
		10 ksps, V_{DD} = 3.0 V	—	20	—	µA
ADC0 Burst Mode, 10-bit single conversions, internal reference, Low power bias settings	I_{ADC}	200 ksps, V_{DD} = 3.0 V	—	485	—	µA
		100 ksps, V_{DD} = 3.0 V	—	245	—	µA
		10 ksps, V_{DD} = 3.0 V	—	25	—	µA
ADC0 Burst Mode, 12-bit single conversions, external reference	I_{ADC}	100 ksps, V_{DD} = 3.0 V	—	505	—	µA
		50 ksps, V_{DD} = 3.0 V	—	255	—	µA
		10 ksps, V_{DD} = 3.0 V	—	50	—	µA
ADC0 Burst Mode, 12-bit single conversions, internal reference	I_{ADC}	100 ksps, V_{DD} = 3.0 V, Normal bias	—	950	—	µA
		50 ksps, V_{DD} = 3.0 V, Low power bias	—	415	—	µA
		10 ksps, V_{DD} = 3.0 V, Low power bias	—	80	—	µA
Internal ADC0 Reference, Always-on[5]	I_{VREFFS}	Normal Power Mode	—	680	790	µA
		Low Power Mode	—	160	210	µA

4.1.3 Reset and Supply Monitor

Table 4.3. Reset and Supply Monitor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
VDD Supply Monitor Threshold	V_{VDDM}		1.95	2.05	2.15	V
Power-On Reset (POR) Threshold	V_{POR}	Rising Voltage on VDD	—	1.2	—	V
		Falling Voltage on VDD	0.75	—	1.36	V
VDD Ramp Time	t_{RMP}	Time to V_{DD} > 2.2 V	10	—	—	µs
Reset Delay from POR	t_{POR}	Relative to V_{DD} > V_{POR}	3	10	31	ms
Reset Delay from non-POR source	t_{RST}	Time between release of reset source and code execution	—	50	—	µs
RST Low Time to Generate Reset	t_{RSTL}		15	—	—	µs
Missing Clock Detector Response Time (final rising edge to reset)	t_{MCD}	F_{SYSCLK} >1 MHz	—	0.625	1.2	ms
Missing Clock Detector Trigger Frequency	F_{MCD}		—	7.5	13.5	kHz
VDD Supply Monitor Turn-On Time	t_{MON}		—	2	—	µs

4.1.4 Flash Memory

Table 4.4. Flash Memory

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Write Time[1,2]	t_{WRITE}	One Byte, F_{SYSCLK} = 24.5 MHz	19	20	21	µs
Erase Time[1,2]	t_{ERASE}	One Page, F_{SYSCLK} = 24.5 MHz	5.2	5.35	5.5	ms
V_{DD} Voltage During Programming[3]	V_{PROG}		2.2	—	3.6	V
Endurance (Write/Erase Cycles)	N_{WE}		20k	100k	—	Cycles

Note:

1. Does not include sequencing time before and after the write/erase operation, which may be multiple SYSCLK cycles.
2. The internal High-Frequency Oscillator 0 has a programmable output frequency, which is factory programmed to 24.5 MHz. If user firmware adjusts the oscillator speed, it must be between 22 and 25 MHz during any flash write or erase operation. It is recommended to write the HFO0CAL register back to its reset value when writing or erasing flash.
3. Flash can be safely programmed at any voltage above the supply monitor threshold (V_{VDDM}).
4. Data Retention Information is published in the Quarterly Quality and Reliability Report.

4.1.7 External Clock Input

Table 4.7. External Clock Input

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Input CMOS Clock Frequency (at EXTCLK pin)	f_{CMOS}		0	—	50	MHz
External Input CMOS Clock High Time	t_{CMOSH}		9	—	—	ns
External Input CMOS Clock Low Time	t_{CMOSL}		9	—	—	ns

4.1.10 Temperature Sensor

Table 4.10. Temperature Sensor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Offset	V_{OFF}	T_A = 0 °C	—	757	—	mV
Offset Error[1]	E_{OFF}	T_A = 0 °C	—	17	—	mV
Slope	M		—	2.85	—	mV/°C
Slope Error[1]	E_M		—	70	—	µV/°
Linearity			—	0.5	—	°C
Turn-on Time			—	1.8	—	µs

Note:
1. Represents one standard deviation from the mean.

4.1.11 1.8 V Internal LDO Voltage Regulator

Table 4.11. 1.8V Internal LDO Voltage Regulator

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Output Voltage	$V_{OUT\_1.8V}$		1.78	1.85	1.92	V

4.1.12 5 V Voltage Regulator

Table 4.12. 5V Voltage Regulator

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Input Voltage Range[1]	V_{REGIN}		3.0	—	5.25	V
Output Voltage on VDD[2]	V_{REGOUT}	Output Current = 1 to 100 mA Regulation range (VREGIN ≥ 4.1 V)	3.1	3.3	3.6	V
		Output Current = 1 to 100 mA Dropout range (VREGIN < 4.1 V)	—	V_{REGIN} – $V_{DROPOUT}$	—	V
Output Current[2]	I_{REGOUT}		—	—	100	mA
Dropout Voltage	$V_{DROPOUT}$	Output Current = 100 mA	—	—	0.8	V

Note:
1. Input range to meet the Output Voltage on VDD specification. If the 5V voltage regulator is not used, VREGIN should be tied to VDD.
2. Output current is total regulator output, including any current required by the device.

4.1.13 Comparators

Table 4.13. Comparators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Response Time, CPMD = 00 (Highest Speed)	t_{RESP0}	+100 mV Differential, V_{CM} = 1.65 V	—	110	—	ns
		-100 mV Differential, V_{CM} = 1.65 V	—	160	—	ns
Response Time, CPMD = 11 (Lowest Power)	t_{RESP3}	+100 mV Differential, V_{CM} = 1.65 V	—	1.2	—	µs
		-100 mV Differential, V_{CM} = 1.65 V	—	4.5	—	µs
Positive Hysteresis Mode 0 (CPMD = 00)	HYS_{CP+}	CPHYP = 00	—	0.4	—	mV
		CPHYP = 01	—	8	—	mV
		CPHYP = 10	—	16	—	mV
		CPHYP = 11	—	32	—	mV
Negative Hysteresis Mode 0 (CPMD = 00)	HYS_{CP-}	CPHYN = 00	—	-0.4	—	mV
		CPHYN = 01	—	-8	—	mV
		CPHYN = 10	—	-16	—	mV
		CPHYN = 11	—	-32	—	mV
Positive Hysteresis Mode 3 (CPMD = 11)	HYS_{CP+}	CPHYP = 00	—	1.5	—	mV
		CPHYP = 01	—	4	—	mV
		CPHYP = 10	—	8	—	mV
		CPHYP = 11	—	16	—	mV
Negative Hysteresis Mode 3 (CPMD = 11)	HYS_{CP-}	CPHYN = 00	—	-1.5	—	mV
		CPHYN = 01	—	-4	—	mV
		CPHYN = 10	—	-8	—	mV
		CPHYN = 11	—	-16	—	mV
Input Range (CP+ or CP-)	V_{IN}		-0.25	—	V_{DD}+0.25	V
Input Pin Capacitance	C_{CP}		—	7.5	—	pF
Internal Reference DAC Resolution	N_{bits}			6		bits
Common-Mode Rejection Ratio	$CMRR_{CP}$		—	70	—	dB
Power Supply Rejection Ratio	$PSRR_{CP}$		—	72	—	dB
Input Offset Voltage	V_{OFF}	T_A = 25 °C	-10	0	10	mV
Input Offset Tempco	TC_{OFF}		—	3.5	—	µV/°

4.3 Absolute Maximum Ratings

Stresses above those listed in Table 4.16 Absolute Maximum Ratings on page 24 may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at http://www.silabs.com/support/quality/pages/default.aspx.

Table 4.16. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T_{BIAS}		-55	125	°C
Storage Temperature	T_{STG}		-65	150	°C
Voltage on VDD	V_{DD}		GND-0.3	4.2	V
Voltage on VREGIN	V_{REGIN}		GND-0.3	5.8	V
Voltage on I/O pins or RSTb	V_{IN}	V_{DD} > 3.3 V	GND-0.3	5.8	V
		V_{DD} < 3.3 V	GND-0.3	V_{DD}+2.5	V
Total Current Sunk into Supply Pin	I_{VDD}		—	200	mA
Total Current Sourced out of Ground Pin	I_{GND}		200	—	mA
Current Sourced or Sunk by any I/O Pin or RSTb	I_{IO}		-100	100	mA
Operating Junction Temperature	T_J	T_A = -40 °C to 85 °C	–40	105	°C
		T_A = -40 °C to 125 °C (I-grade or A-grade parts only)	-40	130	°C

Note:
1. Exposure to maximum rating conditions for extended periods may affect device reliability.

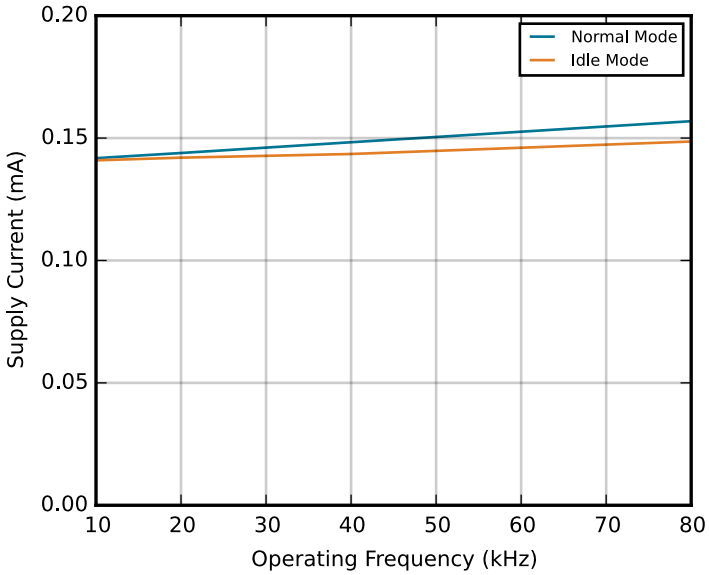

Figure 4.3. Typical Operating Supply Current using LFOSC

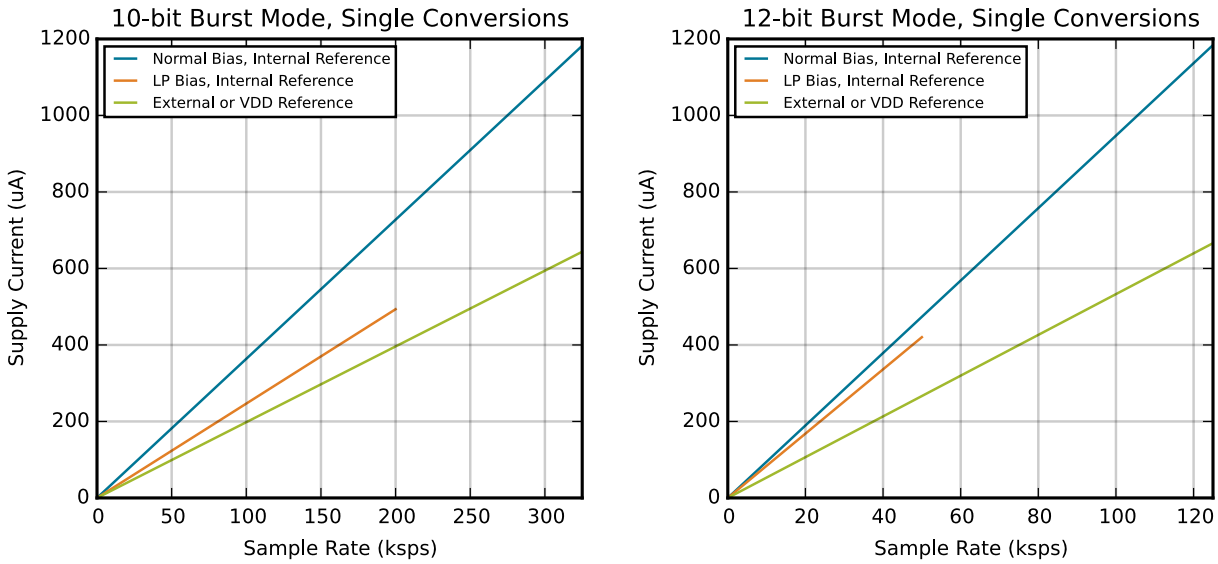

Figure 4.4. Typical ADC0 and Internal Reference Supply Current in Burst Mode

5. Typical Connection Diagrams

5.1 Power

Figure 5.1 Connection Diagram with Voltage Regulator Used on page 29 shows a typical connection diagram for the power pins of the EFM8BB2 devices when the 5 V-to-3.3 V regulator is in use.

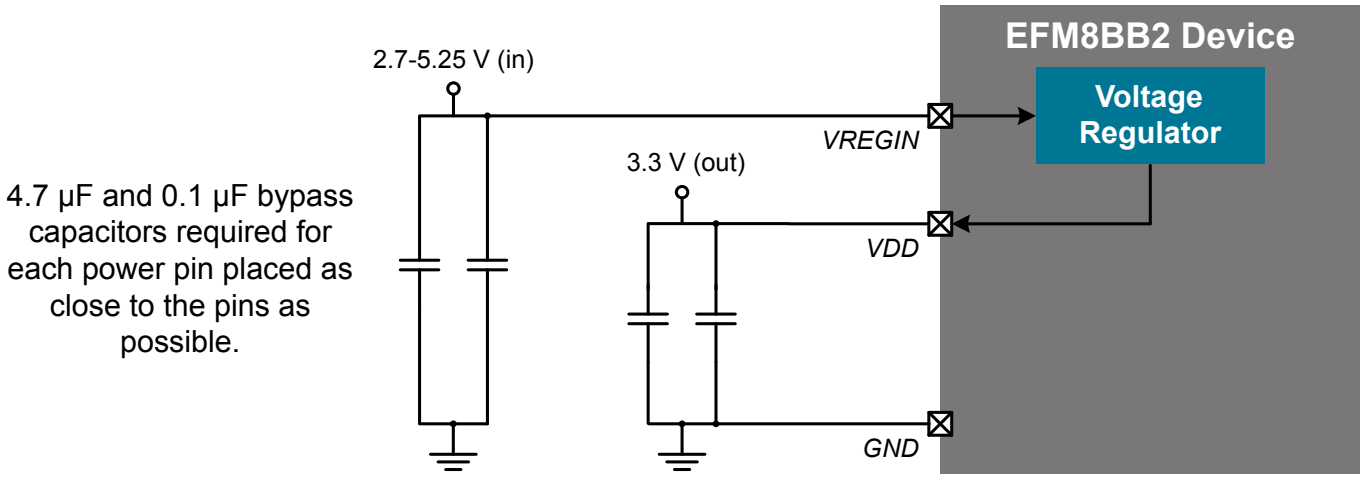

Figure 5.1. Connection Diagram with Voltage Regulator Used

Figure 5.2 Connection Diagram with Voltage Regulator Not Used on page 29 shows a typical connection diagram for the power pins of the EFM8BB2 devices when the internal 5 V-to-3.3 V regulator is not used.

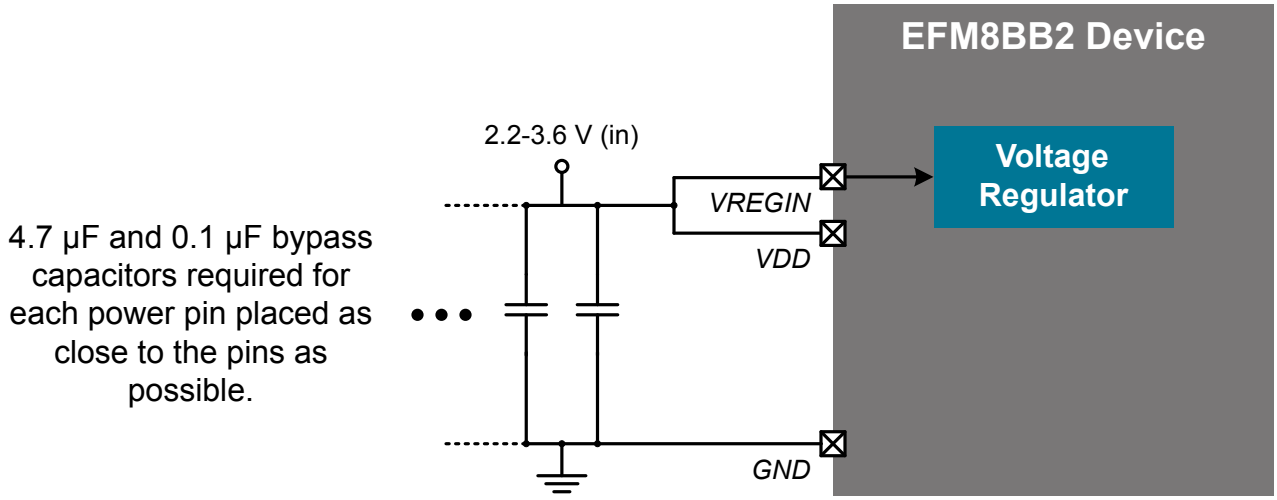

Figure 5.2. Connection Diagram with Voltage Regulator Not Used

5.2 Debug

The diagram below shows a typical connection diagram for the debug connections pins. The pin sharing resistors are only required if the functionality on the C2D (a GPIO pin) and the C2CK (RSTb) is routed to external circuitry. For example, if the RSTb pin is connected to an external switch with debouncing filter or if the GPIO sharing with the C2D pin is connected to an external circuit, the pin sharing resistors and connections to the debug adapter must be placed on the hardware. Otherwise, these components and connections can be omitted.

For more information on debug connections, see the example schematics and information available in AN127: "Pin Sharing Techniques for the C2 Interface." Application notes can be found on the Silicon Labs website (http://www.silabs.com/8bit-appnotes) or in Simplicity Studio.

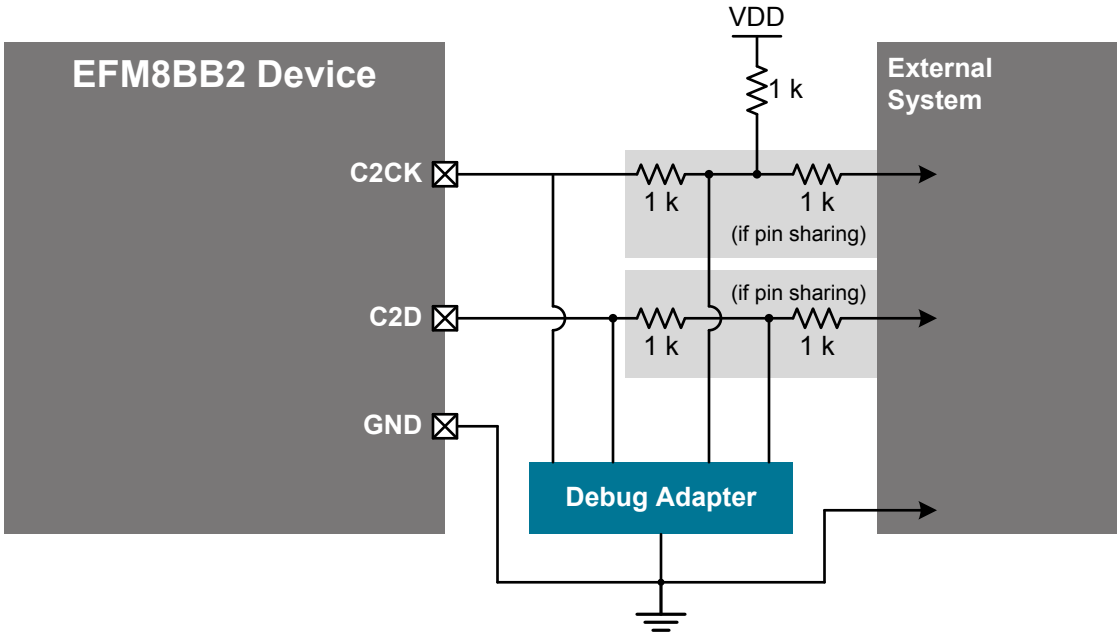

Figure 5.3. Debug Connection Diagram

5.3 Other Connections

Other components or connections may be required to meet the system-level requirements. Application note, "AN203: 8-bit MCU Printed Circuit Board Design Notes", contains detailed information on these connections. Application Notes can be accessed on the Silicon Labs website (www.silabs.com/8bit-appnotes).

6. Pin Definitions

6.1 EFM8BB2x-QFN28 Pin Definitions

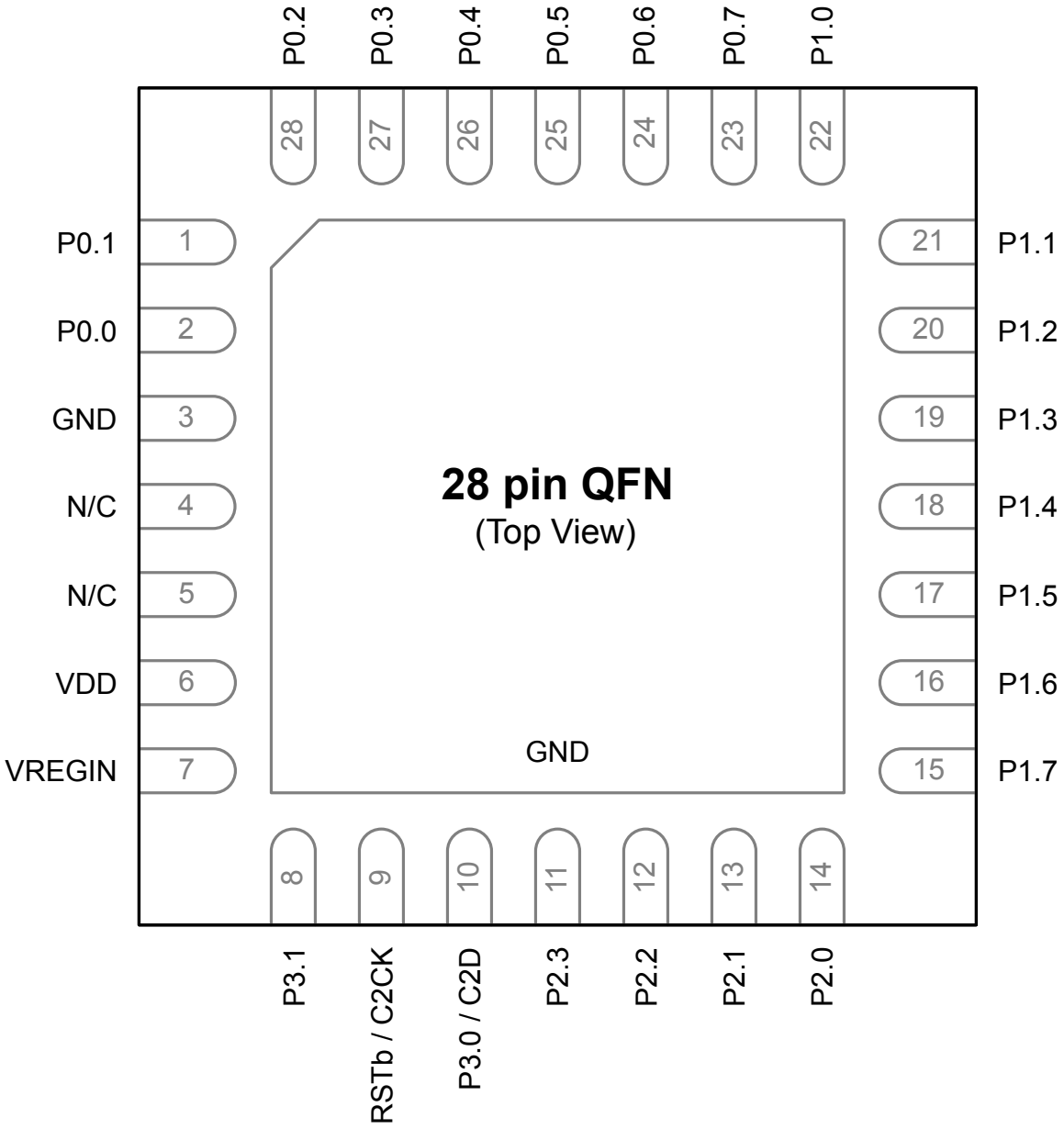

Figure 6.1. EFM8BB2x-QFN28 Pinout

Table 6.1. Pin Definitions for EFM8BB2x-QFN28

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 CMP0P.1 CMP0N.1 AGND
2	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	ADC0.0 CMP0P.0 CMP0N.0 VREF
3	GND	Ground			
4	N/C	No Connection			
5	N/C	No Connection			
6	VDD	Supply Power Input / 5V Regulator Output			
7	VREGIN	5V Regulator Input			
8	P3.1	Multifunction I/O			
9	RST / C2CK	Active-low Reset / C2 Debug Clock			
10	P3.0 / C2D	Multifunction I/O / C2 Debug Data			
11	P2.3	Multifunction I/O	Yes	P2MAT.3	ADC0.23 CP1P.12 CP1N.12
12	P2.2	Multifunction I/O	Yes	P2MAT.2	ADC0.22 CP1P.11 CP1N.11
13	P2.1	Multifunction I/O	Yes	P2MAT.1	ADC0.21 CP1P.10 CP1N.10
14	P2.0	Multifunction I/O	Yes	P2MAT.0	ADC0.20 CP1P.9 CP1N.9
15	P1.7	Multifunction I/O	Yes	P1MAT.7	ADC0.15 CP1P.7 CP1N.7

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
26	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4 UART0_TX	ADC0.4 CMP0P.4 CMP0N.4
27	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3	ADC0.3 CMP0P.3 CMP0N.3
28	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2	ADC0.2 CMP0P.2 CMP0N.2
Center	GND	Ground			

6.3 EFM8BB2x-QFN20 Pin Definitions

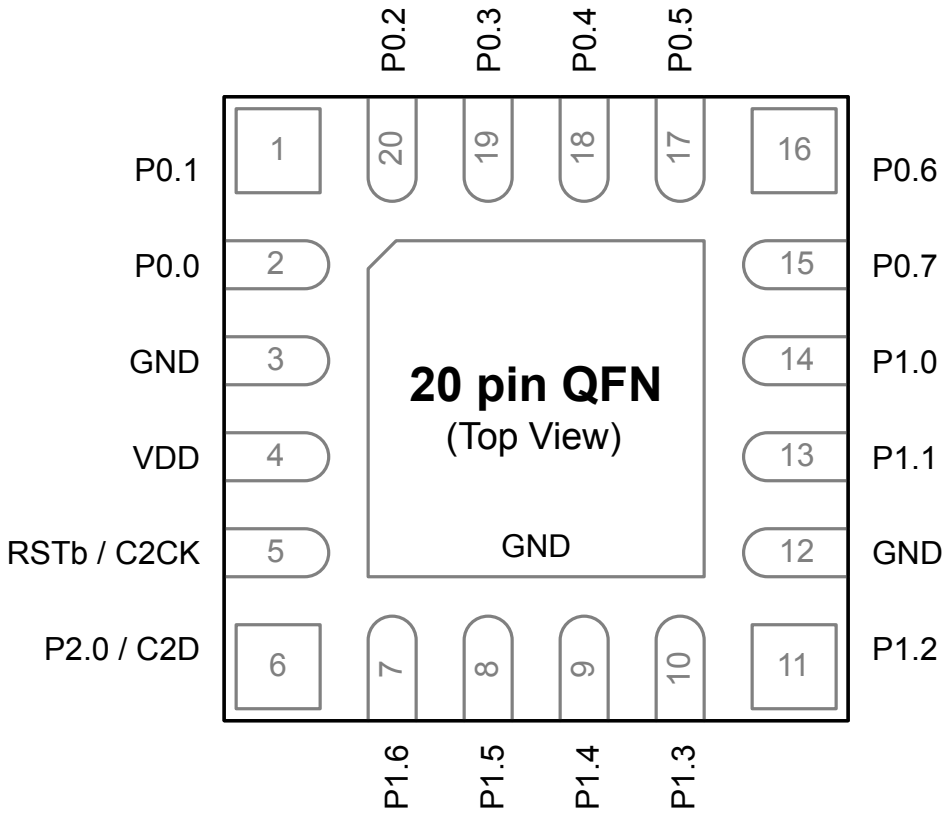

Figure 6.3. EFM8BB2x-QFN20 Pinout

Table 6.3. Pin Definitions for EFM8BB2x-QFN20

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 CMP0P.1 CMP0N.1 AGND
2	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	ADC0.0 CMP0P.0 CMP0N.0 VREF

8.3 QSOP24 Package Marking

Figure 8.3. QSOP24 Package Marking

The package marking consists of:

- PPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).